

ABSTRACT OF THE DISCLOSURE

To provide a nonvolatile memory microcomputer with which a step of testing a microcomputer unit using a logic tester can be omitted, thereby reducing the testing cost.

5 A memory tester supplies test data and expectation data to the nonvolatile memory microcomputer, and the nonvolatile memory microcomputer stores them in a nonvolatile memory. Subsequently, upon receiving an address signal, the nonvolatile memory outputs a test

10 signal and an expectation signal based on test data and expectation data corresponding to the address signal. The test signal is supplied to a circuit block in the microcomputer unit, to drive the circuit block. The circuit block returns a test result signal, which is output

15 to the memory tester together with the expectation signal. The memory tester compares the test result signal and the expectation signal, to judge whether the microcomputer unit operates correctly.